


Search Notes 	Application/Control No. 10598123	Applicant(s)/Patent Under Reexamination SAUAR ET AL.
	Examiner SHEELA C CHAWAN	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	145, 141,	3/29/10	SCC
356	72,237.1, 30	"	"
438	8,4,16,800,199,67,74	"	"
257	E21.525, E23.17,E21.41,E27.12,432,440,E25.00	"	"
356	394, 237.5	"	"
136	249,246,243	"	"
250	206.1,208.6,492.2	"	"
365	201,226, 78, 174, 220	"	"
326	41,39,47	"	"
430	318	"	"
716	4,8	"	"
136	249	10/24/10	SCC
382	141,145	10/24/10	SCC
SEARCH UP-DATE		11/13/10	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	3/29/10	SCC
INVENTOR NAME SEARCH	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	10/24/10	SCC
382/145,141.CCLS.	10/24/10	SCC
136/249,262,243,252,246.CCLS.	10/24/10	SCC
INTERFERENCE SEARCH	10/24/10	SCC
G OOGLE SEARCH "wafer image" "solar cell " images (matching or comparison)	10/24/10	SCC
SEARCH IEEE OR INSPEC DATA BASE.	10/24/10	SCC
SEARCH UP-DATE	10/24/10	SCC
SEARCH UP-DATE	11/13/10	SCC
GOGGLE SEARCH: ((producing or obtaining or generating) wafer image cell image (comparing or match) (ccd or camera or CMOS or IR) filetype:pdf	11/21/10	SCC
SEARCH UP-DATE	11/21/10	SCC

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INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
`382	141, 145	10/24/10	SCC
136	249	10/24/10	SCC

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